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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/693,546	10/23/2003	John R. Chase	ALTRP098/A1185	3624
51501 BEYER WEAV	7590 10/31/2007 VER LLP	EXAMINER		
ATTN: ALTERA			LO, SUZANNE	
P.O. BOX 702: OAKLAND, C			ART UNIT	PAPER NUMBER
,			2128	
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			10/31/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

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	Application No.	Applicant(s)				
	10/693,546	CHASE, JOHN R.				
Office Action Summary	Examiner	Art Unit				
·	Suzanne Lo	2128				
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address				
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 16(a). In no event, however, may a reply be tim 11 apply and will expire SIX (6) MONTHS from 12 cause the application to become ABANDONE:	I. hely filed the mailing date of this communication. D (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on 05 M	arch 2007.	•				
	action is non-final.					
,						
	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims						
4)⊠ Claim(s) <u>1-27</u> is/are pending in the application.	•					
	4a) Of the above claim(s) is/are withdrawn from consideration.					
5) Claim(s) is/are allowed.						
6)⊠ Claim(s) <u>1-27</u> is/are rejected.	·					
7) Claim(s) is/are objected to.						
8) Claim(s) are subject to restriction and/or	election requirement.					
Application Papers		•				
9) The specification is objected to by the Examine	Г.	•				
10) ☑ The drawing(s) filed on 23 October 2003 is/are:		to by the Examiner.				
Applicant may not request that any objection to the						
Replacement drawing sheet(s) including the correct	ion is required if the drawing(s) is ob	jected to. See 37 CFR 1.121(d).				
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.						
Priority under 35 U.S.C. § 119						
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). 						
* See the attached detailed Office action for a list of the certified copies not received.						
• •						
Attachment(s)						
1) Notice of References Cited (PTO-892)	4) Interview Summary					
 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date 	Paper No(s)/Mail Do 5) Notice of Informal F 6) Other:	ate · Patent Application (PTO-152)				
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DETAILED ACTION

1. Claims 1-27 have been presented for examination.

Claim Rejections - 35 USC § 101

35 U.S.C. 101 reads as follows:

Whoever invents or discovers any new and useful process, machine, manufacture, or composition of matter, or any new and useful improvement thereof, may obtain a patent therefor, subject to the conditions and requirements of this title.

2. Claims 25-27 rejected under 35 U.S.C. 101 because the claimed invention is directed to non-statutory subject matter. Specifically, claims 25-27 are directed to software per se as the broadest reasonable interpretation for the means for the claimed apparatus includes software means only (page 19 of the Specification, last paragraph). Furthermore, the invocation of U.S.C. 112, 6th paragraph is invalidated due to lines 15-19 on page 19 of the Specification of the instant application as all possible means for embodiment are disclosed.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

The factual inquiries set forth in *Graham* v. *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

- 1. Determining the scope and contents of the prior art.
- 2. Ascertaining the differences between the prior art and the claims at issue.
- 3. Resolving the level of ordinary skill in the pertinent art.

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4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

3. Claims 1-13 and 17-27 are rejected under 35 U.S.C. 103(a) as being unpatentable over Zaidi et al. (U.S. Patent Application Publication 2002/0038401 A1) in view of Heinkel et al. (U.S. Patent Application Publication 2004/0015739 A1) in view of Whitten (U.S. Patent No. 5,805,795).

As per claim 1, Zaidi is directed to a method ([0029]-[0032]) comprising: a plurality of test designs ([0037]), the plurality of test designs having varied characteristics ([0054]) to allow testing of a design automation tool, wherein generating one of the plurality of test designs comprises: instantiating the I/O structure of a top level module, the top level module having input and output pins ([0048]-[0052]); selecting a plurality of submodules ([0074]) from a design module library ([0055]), wherein cost constraints are used to select the plurality of submodules ([0076]-[0078]); parameterizing the plurality of submodules from the design module library for interconnection with the top level module, the plurality of submodules having input and output lines ([0039, Table 1]); providing logic to interconnect the plurality of parameterized submodules as well as to connect the plurality of parameterized submodules to various input and output pins of the top level module ([0050]) but fails to explicitly disclose generating a plurality of test designs.

Heinkel teaches generating a plurality of test designs ([0057]-[0060]). Specifically, Heinkel [0057]) teaches it is possible to "reconfigure the device under test" which anticipates generating multiple test designs and applying the plurality of test designs to test the design automation tool ([0058]). Zaidi and Heinkel are analogous art because they are from the same field of endeavor, validating an IC with a testbench. It would have been obvious to one of ordinary skill in the art at the time of the invention to combine the method of validating an IC of Zaidi with the method of generating test designs of Heinkel in order to allow testing of different

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designs without needing to recompile the VHDL testbench for each test design (Heinkel, [0058]).

The combination of Zaidi and Heinkel fail to explicitly disclose wherein a probabilistic function is applied to select submodules of different types from a library. Whitten teaches selecting applying a probabilistic function to select submodules of different types from a library to generate a plurality of test designs to test a software program product (column 7, lines 10-56 and column 4, line 64-column 5, line 2). Zaidi, Heinkel, and Whitten are analogous art because they are from the same field of endeavor, test design generation. It would have been obvious to one of ordinary skill in the art at the time of the invention to combine the method of generating a plurality of test designs of Zaidi and Heinkel with the method of selection of a plurality of test designs of Whitten in order to maximize the number of code blocks that are exercised in the software product and minimizes the execution time for the tests (Whitten, column 2, lines 20-24).

As per claim 2, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 1, wherein the design automation tool is used to implement hardware descriptor language designs on a programmable chip (Zaidi, [0031]).

As per claim 3, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 1, wherein the design automation tool is used to implement designs on an ASIC (Zaidi, [0029]).

As per claim 4, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 1, wherein instantiation constraints are used to select the plurality of submodules (Zaidi, [0085]).

As per claim 5, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 1, wherein the design automation tool is a synthesis or a place and route tool (Zaidi, [0032]).

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As per claim 6, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 1, wherein providing logic to interconnect the plurality of parameterized modules comprises identifying inputs and outputs (Zaidi, [0048]-[0060]).

As per claim 7, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 6, wherein inputs comprise input pins of the top level module, submodule output lines, and registers (Zaidi, [0048]-[0060]).

As per claim 8, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 6, wherein outputs comprise output pins of the top level module, submodule input lines, and registers (Zaidi, [0048]-[0060]).

As per claim 9, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 8, wherein providing logic to interconnect the plurality of parameterzied modules but does not disclose classifying inputs and outputs as clock lines, control lines, and data lines. Official notice is taken with respect to this limitation. Specifically it would have been obvious to one of ordinary skill in the art at the time of Applicants invention to have this feature in order to prevent errors when interconnecting inputs and outputs.

As per claim 10, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 8, wherein generating one of the plurality of test designs further comprises: generating randomized logic (Zaidi, [0048]-[0060])

As per claim 11, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 10, randomized is generated logic to drive outputs (Zaidi, [0047]).

As per claim 12, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 10, wherein generating randomized logic comprises directly wiring outputs to inputs, generating a logic expression using inputs, generating a mathematical expression using inputs, or generating decision logic (Zaidi, [0047]).

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As per claim 13, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 6, but fails to disclose wherein parameterizing the plurality of submodules comprises defining interfaces, data width, and the type of signal for input and output lines associated with the submodule.

Official notice is taken with respect to this limitation. Specifically it would have been obvious to one of ordinary skill in the art at the time of Applicants invention to have this feature in order to prevent errors when interconnecting inputs and outputs.

As per claim 15, the combination of Zaidi, Heinkel, and Whitten already discloses the method of claim 6, wherein generating one of the plurality of test design further comprises selecting a clock structure for each output (Zaidi, [0047]).

As per claims 17-24, Zaidi discloses a computer system ([0029]-[0032]), comprising: memory operable to hold information associated with a design module library ([0025]), a processor coupled to memory ([0025]), the processor configured to execute a method with the same limitations of claim 1 and wherein a submodules of different types are randomly selected from the library (Whitten, column 6, lines 63-67) is therefore rejected over the same art combination.

As per claim 25-27, Zaidi is directed to an apparatus for generating test a testbench ([0029]-[0032]), the apparatus comprising: means for a method with the limitations of claim 1 and is therefore rejected over the same art combination.

4. Claims 14 and 16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Zaidi et al. (U.S. Patent Application Publication 2002/0038401 A1) and Heinkel et al. (U.S. Patent Application Publication 2004/0015739 A1) in view of Whitten (U.S. Patent No. 5,805,795) in further view of Goossens ("Design of Heterogeneous ICs for Mobile and Personal Communication Systems").

As per claim 14, the combination of Zaidi, Heinkel, and Whitten is directed to the method of claim 6, wherein submodules comprise memory and timers ([0037]) but fails to disclose wherein

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submodules comprise adders and phase lock loops. Goossens teaches submodules comprising of adders and phase lock loops (page 524-525, Figure 1, Section 3.2). Zaidi, Heinkel, and Goossens are analogous art because they are all from the same field of endeavor, validating an IC. It would have been obvious to one of ordinary skill in the art at the time of the invention to combine the method of validating an IC with a testbench of Zaidi, Heinkel, and Whitten with the adders and phase lock loops of Goossens in order to allow the design of heterogeneous IC architecture (page 524, Section 1).

As per claim 16, the combination of Zaidi, Heinkel, and Whitten is directed to the method of claim 15, but fails to specifically disclose wherein clock structures include a plurality of synchronous and asynchronous structures. Goossens teaches clock structures that include a plurality of synchronous and asynchronous structures (page 525-526, Section 3.3). Zaidi, Heinkel, and Goossens are analogous art because they are all from the same field of endeavor, validating an IC. It would have been obvious to one of ordinary skill in the art at the time of the invention to combine the method of validating an IC with a testbench of Zaidi, Heinkel, and Whitten with the clock structures of Goossens in order to implement handshaking, protocol control, and synchronization functionalities for heterogeneous IC architecture (page 525-526, Section 3.3).

Response to Arguments

- Applicant's arguments filed 10/25/07 have been fully considered but they are not persuasive. 5.
- 35 U.S.C. 101 rejections of claims 1-24 have been withdrawn. Rejection of claims 25-27 are 6. maintained as they are still directed to software per se which is nonstatutory. The processing means and interface means can still be entirely embodied as software.
- Applicant's arguments with respect to the prior art rejections have been considered but are moot 7. in view of the new grounds of rejection.

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8. Furthermore, while Applicant states "Both Heinkel and Zaidi possibly describe scripts and simulations that are used to test a physical block or a "new block" "that does not prohibit the scripts and simulations of Heinkel and Zaidi to allow testing of a design automation tool. Applicant is arguing intended use ("to allow testing of a design automation tool" and "to test the design automation tool"), a recitation of the intended use of the claimed invention must result in a structural difference between the claimed invention and the prior art in order to patentably distinguish the claimed invention from the prior art. If the prior art structure is capable of performing the intended use, then it meets the claim.

Conclusion

Applicant's amendment necessitated the new grounds of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

- 9. The prior art made of record is not relied upon because it is cumulative to the applied rejection.

 These references include:
 - 1. U.S. Patent No. 6,477,691 B1 issued to Bergamashi/Rab et al. on 11/05/02.
 - 2. U.S. Patent Application Publication No. 2004/0015792 A1 published by Kubista on 01/22/04.

3. U.S. Patent No. 6,053,947 issued to Parson on 04/25/00.

4. "ASIC to FPGA Design Methodology & Guidelines" published by Altera in July 2003.

5. U.S. Patent No. 7,085,702 issued to Hwang et al. on 08/01/06.

6. U.S. Patent Application Publication No. 2004/0210798 Al..

7. U.S. Patent No. 6,907,550 B2 issued to Webser et al. on 06/14/05.

8. U.S. Patent No. 6,378,088 B1 issued to Mongan on 04/23/02.

9. U.S. Patent No. 6,189,116 B1 issued to Mongan et al. on 02/13/01.

10. All Claims are rejected.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Suzanne Lo whose telephone number is (571)272-5876. The examiner can normally be reached on M-F, 8-4:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Kamini Shah can be reached on (571)272-2297. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Suzanne Lo Patent Examiner Art Unit 2128

SL 10/25/07

SUPERVISORY PATENT EXAMINER